Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/812,892	BONAQUIST ET AL.	
Examiner	Art Unit	
TUYEN T. NGUYEN	2832	

	SEAR	CHED	
Class	Subclass	Date	Examiner
336	55-62	2/18/2006	TTN
62	52.1, 62	2/18/2006	TTN
165	128-130	2/18/2006	TTN
ugdated		5/9/06	FTN
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
Same	above	5/9/06	TIN		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMF
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